Search Notes



Appl	ication/Control	No.	

Applicant(s)/Patent under Reexamination

10/644,370

Examiner

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SEARCHED				
Class	Subclass	Date	Examiner	
606	4-6,10-12	7/22/2005	AF	
128	898	7/22/2005	AF	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		1, 31	,	
Interference Search Histor Printout		7/22/2005	AF	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Search; STIC search; and EAST search: Classification (IS&R); and Text (BRS)	7/22/2005	AF		
Searched Data Basis: USPAT; USPGPUB; EPO; JPO; DERWENT; and IBM_TDB.	7/22/2005	AF		
See the attached "Search History."	7/22/2005	AF		